

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	09/523,886	GRDINA ET AL.
	<b>Examiner</b> Shin-Lin Chen	<b>Art Unit</b> 1632

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
514	1		
435	4		
435	6		
AU interference search		4/21/2005	<i>gm</i>